



## 47 CFR PART 15 SUBPART B

# TEST REPORT

of

### Mobile Phone

Model Name: Z11  
Trade Name: LANIX  
Brand Name: LANIX  
Report No.: SH11050009E01  
FCC ID: ZC4Z11

*prepared for*

**Corporativo Lanix S.A. de C.V.**

Carretera Internacional Hermosillo-Nogales KM 8.5 Hermosillo Sonora Mexico

*prepared by*

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**Bluetooth®**

**CTIA Authorized Test Lab**

LAB CODE 20081223-00

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## 1. TEST CERTIFICATION

Equipment under Test: Mobile Phone

Trade Name: LANIX

Brand Name: LANIX

Model Name: Z11

FCC ID: ZC4Z11

Applicant: Corporativo Lanix S.A. de C.V.

Applicant Address: Carretera Internacional Hermosillo- Nogales KM 8.5 Hermosillo  
Sonora Mexico

Manufacturer: Shanghai Huaqin Telecom Technology Co.,Ltd.

Manufacturer Address: Building1,399 Keyuan Road,Pudong district,Shanghai,China

Test Standards: 47 CFR Part 15 Subpart B

ANSI C63.4-2003

Test Date(s): 2011-5-17~2011-5-18

Test Result: PASS

### \* We Hereby Certify That:

The equipment under test was tested by Shenzhen Electronic Product Quality Testing Center Morlab Laboratory. The test data, data evaluation, test procedures and equipment configurations shown in this report were made in accordance with the requirement of related FCC rules.

The test results of this report only apply for the tested sample equipment identified above. The test report shall be invalid without all the signatures of the test engineer, the reviewer and the approver.

Tested by:

Zhang Wenjie  
Zhang Wenjie

Dated:

2011.5.20

Reviewed by:

Zhang Jun  
Zhang Jun

Dated:

2011.5.20

Approved by:

Wei Bei  
Wei Bei

Dated:

2011.5.20



## 2. GENERAL INFORMATION

### 2.1 EUT Description

EUT Type.....: Mobile Phone  
Model Name .....: Z11  
Hardware Version .....: V2.0  
Software Version.....: ZL109B\_45A0\_V0\_0\_D  
Frequency .....: GSM850/1900 MHz ,ISM 2.4GHz  
Modulation Type.....: GSM/GPRS : GMSK  
Bluetooth (1Mbps) : GFSK  
Bluetooth EDR (2Mbps) :  $\pi/4$ -DQPSK  
Bluetooth EDR (3Mbps) : 8-DPSK  
Power Supply.....: Battery  
Brand name: LANIX  
Mode Name.: Z11  
Capacitance: 1000mAh  
Rated voltage: 3.7V  
Charge limited: 4.2V  
Manufacturer: SHENZHEN ZEALWIN ELECTRONIC CO.,LTD  
AC Adapter (Charger for Battery)  
Brand name: LANIX  
Mode Name.: ZT-666-E0500  
Rated Input: AC 100-240V,200mA,50/60Hz  
Rated Output: DC 5V,500mA  
Manufacturer: SHENZHEN AOHA TECHNOLOGY CO.,LTD. ,

Note 1: For a more detailed description, please refer to Specification or User's Manual supplied by the applicant and/or manufacturer.

## 2.2 Test Standards and Results

EMISSION			
Standard	Item	Result	Remarks
FCC 47 CFR Part 15 Subpart B ANSI C63.4-2003	Conducted (Main Port)	PASS	Meet Class B limit
	Radiated	PASS	Meet Class B limit

## 2.3 Facilities and Accreditations

### 2.3.1 Facilities

Shenzhen Electronic Product Quality Testing Center Morlab Laboratory is a testing organization accredited by China National Accreditation Service for Laboratories (CNAS) according to ISO/IEC 17025. The accreditation certificate number is L1659.

All measurement facilities used to collect the measurement data are located at Electronic Testing Building, Shahe Road, Xili, Nanshan District, Shenzhen 518055 CHINA. The test site is constructed in conformance with the requirements of ANSI C63.7, ANSI C63.4 and CISPR Publication 22; the FCC registration number is 741109.

### 2.3.2 Test Environment Conditions

During the measurement, the environmental conditions were within the listed ranges:

Temperature (°C):	20 – 25
Relative Humidity (%):	40 – 60
Atmospheric Pressure (kPa):	106



### 3. TEST CONDITIONS SETTING

#### 3.1 Test Mode

The test modes of the EUT are showed as below:

Mode 1. EUT+PC Mode

The EUT configuration of the emission test is EUT + Micro SD card + Battery + PC.

In this test mode, a connection was established between the EUT and a PC; data was transmitted between EUT and the PC, and maintained during the measurement.

#### 3.2 Description Of Support Units

The EUT has been tested as an independent unit together with other necessary accessories or support units. The following support units or accessories were used to form a representative test configuration during the tests.

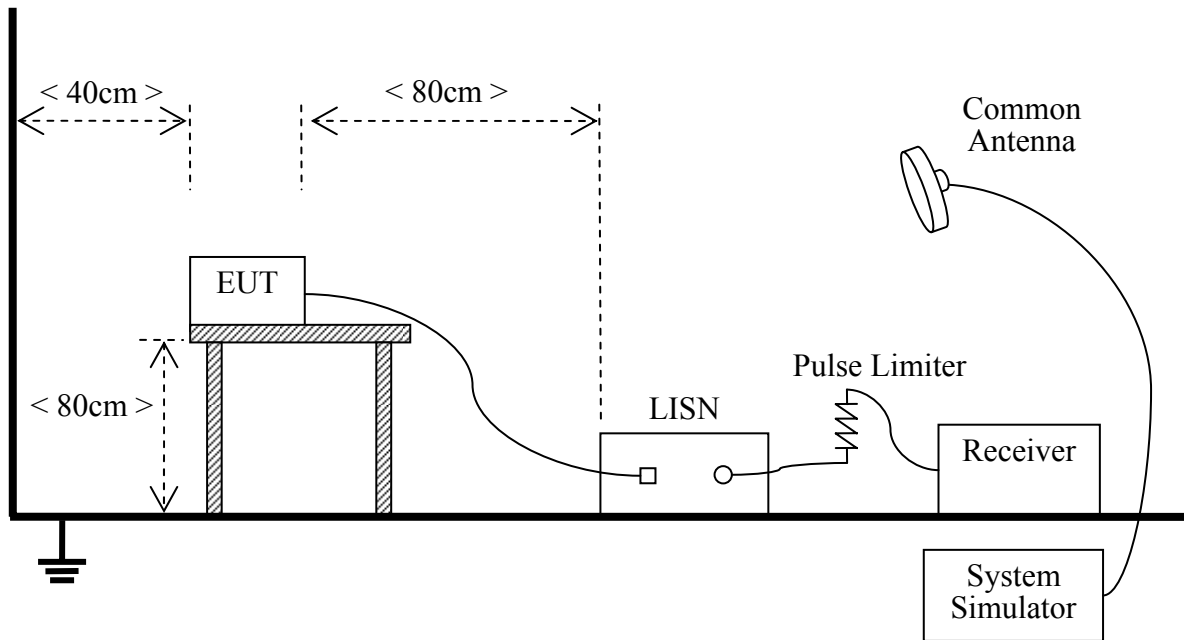
No.	Equipment	Model No.	Serial No.	Trade Name
1	Notebook	HP520	CDP7450MTI	HP
2	Micro SD card	1#	1#	N/A

Note: Grounding was established in accordance with the manufacturer's requirements and conditions for the intended use.

### 3.3 Test Setup and Equipments List

#### 3.3.1 Conducted Emission

##### A. Test Setup:



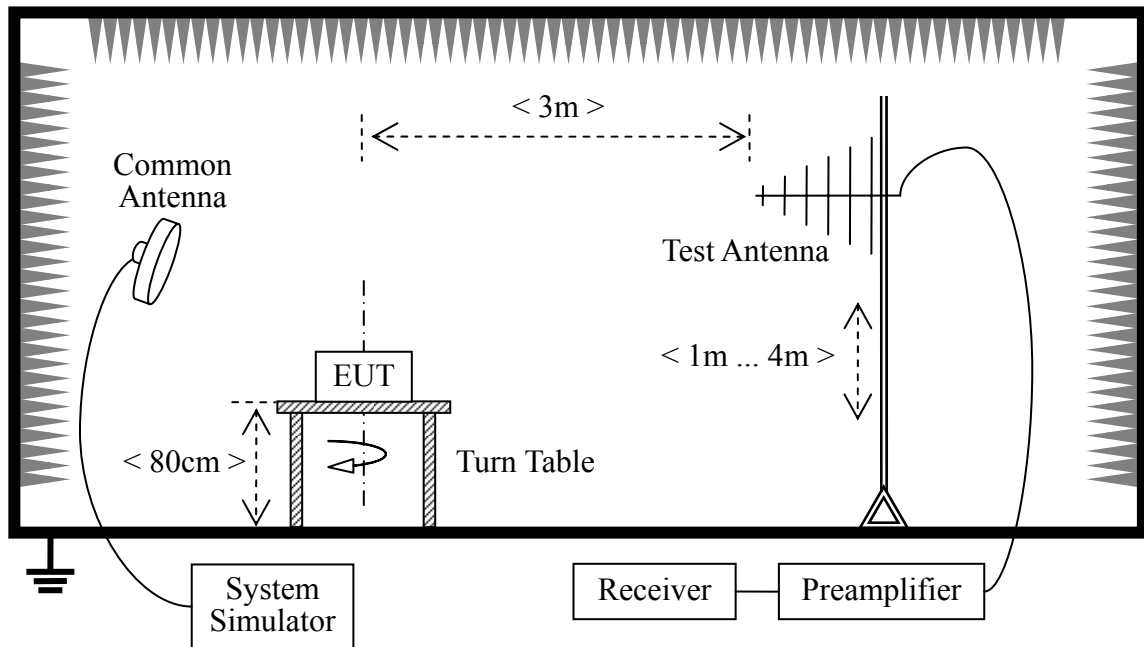
The EUT is placed on a 0.8m high insulating table, which stands on the grounded conducting floor, and keeps 0.4m away from the grounded conducting wall. The EUT is connected to the power mains through a LISN which provides  $50\Omega/50\mu\text{H}$  of coupling impedance for the measuring instrument. The Common Antenna is used for the call between the EUT and the System Simulator (SS). A Pulse Limiter is used to protect the measuring instrument. The factors of the whole test system are calibrated to correct the reading.

##### B. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due
Receiver	Rohde&Schwarz	ESCI3	100666	2010.09	1year
LISN	Rohde&Schwarz	ENV216	812744	2010.09	1year
System Simulator	Rohde&Schwarz	CMU200	105571	2010.09	1year
Personal Computer	Lenovo	(n.a.)	(n.a.)	(n.a.)	(n.a.)

### 3.3.2 Radiated Emission

#### A. Test Setup:



The test is performed in a 3m Semi-Anechoic Chamber; the antenna factor, cable loss and so on of the site (factors) is calculated to correct the reading. The EUT is placed on a 0.8m high insulating Turn Table, and keeps 3m away from the Test Antenna, which is mounted on a variable-height antenna master tower. The Common Antenna is used for the call between the EUT and the System Simulator (SS).

#### B. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due
Receiver	Rohde&Schwarz	ESCI3	100666	2010.09	1year
Full-Anechoic Chamber	Albatross	9m*6m*6m	(n.a.)	2010.09	1year
Test Antenna - Bi-Log	Rohde&Schwarz	HL562	100385	2010.09	1year
System Simulator	Rohde&Schwarz	CMU200	105571	2010.09	1year
Personal Computer	Lenovo	(n.a.)	(n.a.)	(n.a.)	(n.a.)



## 4. 47 CFR PART 15B REQUIREMENTS

### 4.1 Conducted Emission

#### 4.1.1 Requirement

According to FCC section 15.107, the radio frequency voltage that is conducted back onto the AC power line on any frequency within the band 150kHz to 30MHz shall not exceed the limits in the following table, as measured using a 50 $\mu$ H/50 $\Omega$  line impedance stabilization network (LISN).

Frequency range (MHz)	Conducted Limit (dB $\mu$ V)	
	Quai-peak	Average
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5- 30	60	50

NOTE:

- a) The limit subjects to the Class B digital device.
- b) The lower limit shall apply at the band edges.
- c) The limit decreases linearly with the logarithm of the frequency in the range 0.15 - 0.50MHz.

#### 4.1.2 Test Description

See section 3.3.1 of this report.

#### 4.1.3 Test Result

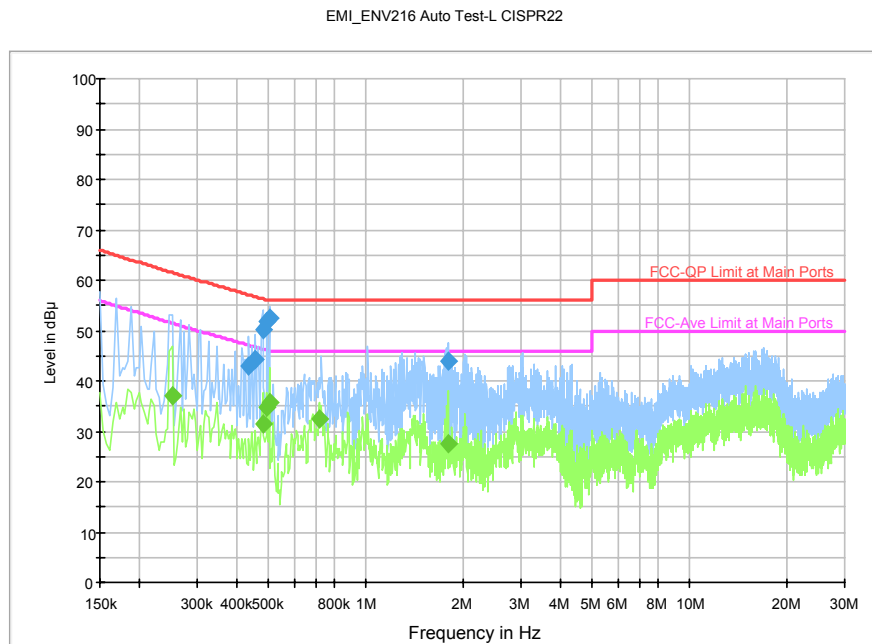
The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed. All test modes are considered, refer to recorded points and plots below.

**A. Test Verdict Recorded for Suspicious Points:**

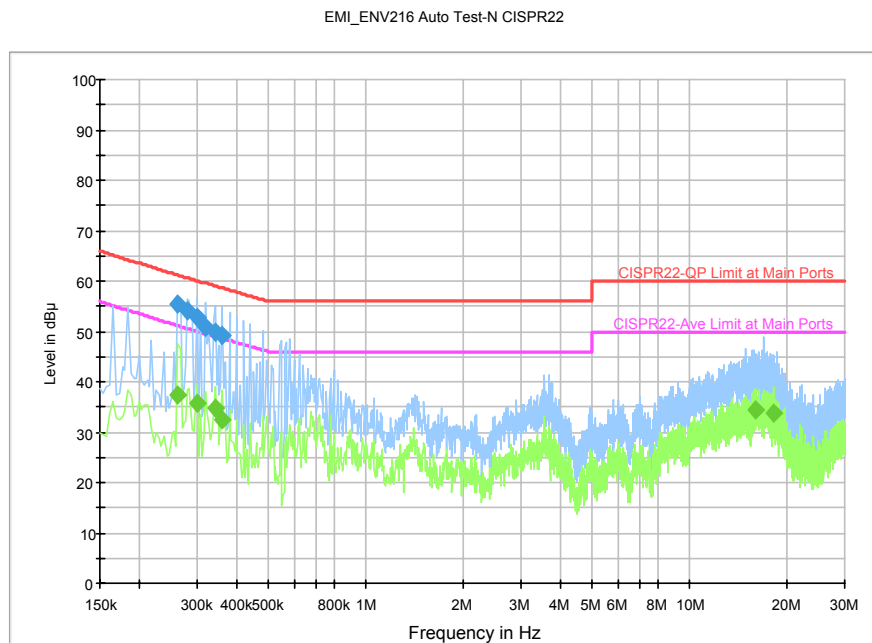
Frequency (MHz)	QuasiPeak (dB $\mu$ V)	Meas. Time (ms)	Band width (kHz)	Line	Corr. (dB)	Margin (dB)	Limit (dB $\mu$ V)	Comment
0.261938	55.6	150.000	9.000	N	9.6	5.6	61.2	PASS
0.280594	54.2	150.000	9.000	N	9.6	6.4	60.6	PASS
0.299250	52.8	150.000	9.000	N	9.6	7.3	60.1	PASS
0.317906	50.9	150.000	9.000	N	9.7	8.7	59.6	PASS
0.340294	49.7	150.000	9.000	N	9.7	9.3	59.0	PASS
0.358950	49.3	150.000	9.000	N	9.7	9.3	58.6	PASS
0.433575	43.1	150.000	9.000	L	9.7	14.0	57.1	PASS
0.452231	44.3	150.000	9.000	L	9.7	12.5	56.8	PASS
0.478350	50.1	150.000	9.000	L	9.6	6.2	56.3	PASS
0.493275	52.0	150.000	9.000	L	9.7	4.1	56.1	PASS
0.500738	52.4	150.000	9.000	L	9.7	3.6	56.0	PASS
1.795481	43.9	150.000	9.000	L	9.8	12.1	56.0	PASS

Frequency (MHz)	Average (dB $\mu$ V)	Meas. Time (ms)	Band width (kHz)	Line	Corr. (dB)	Margin (dB)	Limit (dB $\mu$ V)	Comment
0.261938	37.5	150.000	9.000	N	9.6	13.6	51.1	PASS
0.299250	35.7	150.000	9.000	N	9.6	14.3	50.0	PASS
0.340294	34.9	150.000	9.000	N	9.7	14.1	49.0	PASS
0.358950	32.5	150.000	9.000	N	9.7	16.1	48.6	PASS
15.892144	34.6	150.000	9.000	N	10.3	15.4	50.0	PASS
18.022688	33.9	150.000	9.000	N	10.3	16.1	50.0	PASS
0.250744	37.1	150.000	9.000	L	9.6	14.4	51.5	PASS
0.478350	31.3	150.000	9.000	L	9.6	15.0	46.3	PASS
0.493275	34.6	150.000	9.000	L	9.7	11.5	46.1	PASS
0.500738	35.8	150.000	9.000	L	9.7	10.2	46.0	PASS
0.713419	32.3	150.000	9.000	L	9.7	13.7	46.0	PASS
1.795481	27.4	150.000	9.000	L	9.8	18.6	46.0	PASS

## B. Test Plot:



(Plot: L Phase)



(Plot: N Phase)

## 4.2 Radiated Emission

### 4.2.1 Requirement

According to FCC section 15.109, the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

Frequency range (MHz)	Field Strength	
	$\mu\text{V/m}$	$\text{dB}\mu\text{V/m}$
30 - 88	100	40.0
88 - 216	150	43.5
216 - 960	200	46.0
Above 960	500	54.0

NOTE:

- Field Strength ( $\text{dB}\mu\text{V/m}$ ) =  $20 \cdot \log[\text{Field Strength } (\mu\text{V/m})]$ .
- In the emission tables above, the tighter limit applies at the band edges.

### 4.2.2 Test Description

See section 3.2.2 of this report.

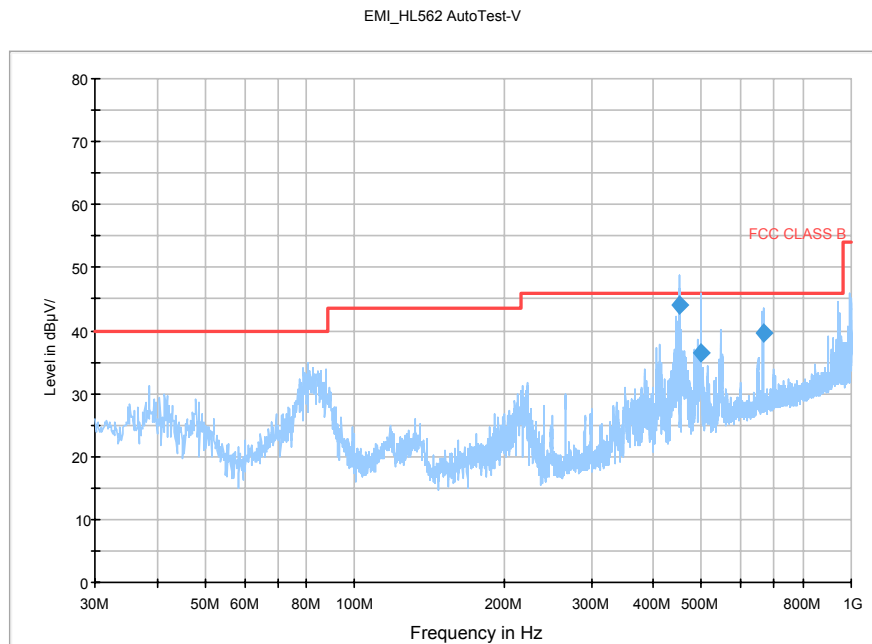
### 4.2.3 Test Result

The maximum radiated emission is searched using PK, QP and AV detectors; the emission levels more than the limits, and that have narrow margins from the limits will be re-measured with AV and QP detectors. Both the vertical and the horizontal polarizations of the Test Antenna are considered to perform the tests. All test modes are considered, refer to recorded points and plots below.

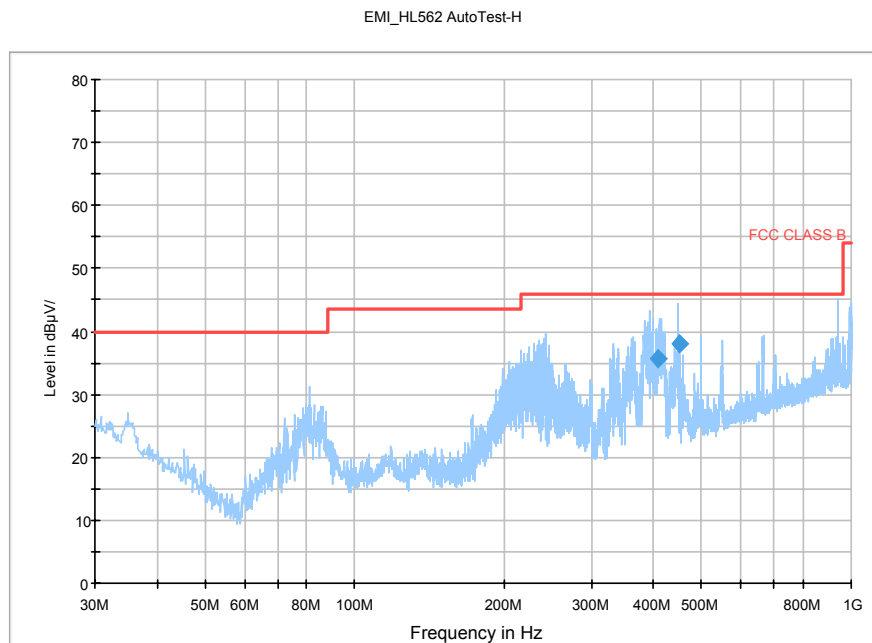
#### A. Test Plot:

No.	@Frequency (MHz)	Emission Level ( $\text{dB}\mu\text{V/m}$ )		Quasi-Peak Limit ( $\text{dB}\mu\text{V/m}$ )	Margin ( $\text{dB}\mu\text{V/m}$ )	Result
		QP ( $\text{dB}\mu\text{V/m}$ )	Antenna Polarization			
1	449.395625	44.1	V	46.0	1.9	PASS
2	499.558125	36.6	V	46.0	9.4	PASS
3	666.301250	39.7	V	46.0	6.3	PASS
4	408.399375	35.6	V	46.0	10.4	PASS
5	449.564375	38.1	V	46.0	7.9	PASS

## B. Test Plot:



(Plot: Test Antenna Vertical)



(Plot: Test Antenna Horizontal)

**\*\* END OF REPORT \*\***